


<b>Search Notes</b>  	<b>Application/Control No.</b>  10602355	<b>Applicant(s)/Patent Under Reexamination</b>  SCHIFF, LEONARD N.
	<b>Examiner</b>  RICHARD CHAN	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
455	12.1, 427, 428, 11.1, 13.1, 13.2,	5/17/11	RC

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted Raymond Dean (Primary) regarding prior art search	1/16/12	RC
Consulted Yuwen Pan for prior art and 112 1st paragraph rejection for claim 28	1/29/12	RC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
455	12.1, 427, 428, 11.1	8/24/12	RC

/RICHARD CHAN/ Examiner.Art Unit 2618	
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